



Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	Docket Number 509982000100	Application Number 09/770,997
	Applicant Xinhui NIU and Nickhil JAKATDAR	
	Filing Date January 25, 2001	Group Art Unit 2621 2877
	Mailing Date April 9, 2002	

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
	1.	7/21/92	5,131,752	Yu et al.			
	2.	11/17/92	5,164,790	McNeil et al.			
	3.	3/4/97	5,607,800	Ziger			
	4.	4/14/98	5,739,909	Blayo et al.			
	5.	11/10/98	5,835,225	Thakur			
	6.	2/2/99	5,867,276	McNeil et al.			
	7.	10/5/99	5,963,329	Conrad et al.			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
	8.	N. W. Ashcroft et al., "Solid State Physics", Saunders College Philadelphia, 1976, pgs. 133-135.
	9.	R. M. A. Azzam et al., "Ellipsometry and Polarized Light", Elsevier Science B. V., 1987, book.
	10.	Ch. M. Bishop, "Neural Networks for Pattern Recognition", Ch. 4, 1995, pp. 117-161.
	11.	S. Bushman et al., "Scatterometry Measurements for Process Monitoring of Gate Etch", AEC/APC Workshop IX, Sematech, Sept. 20-24, 1997, pp. 148-158.
	12.	G. Granet et al., "Efficient implementation of the coupled-wave method for metallic lamellar in TM polarization", J. Opt. Soc. Am. vol. 13, no. 5, May 1996, pp. 1019-1023.
	13.	O. S. Heavens, "Optical Properties of Thin Solid Films", Dover Publications, Inc. 1955, book.
	14.	P. Lalanne et al., "Highly improved convergence of the coupled-wave method for TM polarization", J. Opt. Soc. Am. vol. 13, no. 4, April 1996, pp. 779-784.
	15.	L. Li et al., "Convergence of the coupled-wave method for metallic lamellar diffraction gratings", J. Opt. Soc. Am. vol. 10, no. 6, June 1993, pp. 1184-1189.

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	16.	D. Maystre, "A new general integral theory for dielectric coated gratings", J. of Opt. Soc. of Amer. vol. 68 (4), Apr. 78, pp. 189-194.
	17.	M. G. Moharam et al., "Rigorous coupled-wave analysis of planar-grating diffraction", J. Opt. Soc. Am. vol. 71, no. 7/July 1981, pp. 811-818.
	18.	M. G. Moharam et al., "Formulation for stable and efficient implementation of the rigorous coupled-wave analysis of binary gratings", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1068-1076.
	19.	Moharam et al., "Stable implementation of the rigorous coupled-wave analysis for surface - relief gratings: enhanced transmittance matrix approach", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1077-1086.
	20.	M. Nevriere et al., "Systematic Study of Resonances of Holographic Thin Film Couplers", Optics Com. vol. 9 (1), 1973, pp. 205-209.
	21.	A. R. Neureuther et al., "Numerical Methods for the Analysis of Scattering from Nonplanar Periodic Structures", URSI Symposium on Electromag. Waves, 1969, pp. 185-188.
	22.	W. H. Press et al., "Numerical Recipes in C", Art of Scien. Computing 2nd Ed., 1986, pp. 29-38.
	23.	J. A. Rice, "Mathematical Statistics and Data Analysis" sec. ed., ch. 14, Duxbury Press, 1995, pp. 507-570.

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